

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	((handwri\$5 or handraw\$3) near7 (recogni\$4 or identif\$7) same (pen or pencil) same (paper or cardboard or plastic or metal or cloth)).clm.	US-PGPUB	OR	ON	2006/05/12 12:46
L2	0	((handwri\$5 or handraw\$3) and (pen or pencil) and (conventional with (medium or writing)) and (scan\$4) and (recogniz\$4) and (paper or cardboard or plastic or metal or cloth)).clm.	US-PGPUB	OR	ON	2006/05/12 12:47
L3	0	((handwri\$5 or handraw\$3) and (pen or pencil) and (conventional same (medium or writing)) and (scan\$4) and (recogniz\$4) and (paper or cardboard or plastic or metal or cloth)).clm.	US-PGPUB	OR	ON	2006/05/12 12:48
L4	0	((handwri\$5) and (pen or pencil) and (conventional same (medium or writing)) and (scan\$4) and (recogniz\$4) and (paper or cardboard or plastic or metal or cloth)).clm.	US-PGPUB	OR	ON	2006/05/12 12:48
L5	0	((hand\$8) and (pen or pencil) and (conventional same (medium or writing)) and (scan\$4) and (recogniz\$4) and (paper or cardboard or plastic or metal or cloth)).clm.	US-PGPUB	OR	ON	2006/05/12 12:48

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

[Search Session History](#)[BROWSE](#)[SEARCH](#)[IEEE Xplore GUIDE](#)

Edit an existing query or
compose a new query in the
Search Query Display.

Select a search number (#)
to:

- Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- Delete a search
- Run a search

Fri, 12 May 2006, 1:02:37 PM EST

Search Query Display

Recent Search Queries

#1 (((((handwri* or handraw*) <near/7> (recogni* or identif* or determin*)) <paragraph> (pen or pencil) <paragraph> (paper or cardboard or plastic or metal or cloth))<in>metadata)

#2 (((((handwri* or handraw*) <near/7> (command or mark* or edit* or add* or delet*)) <paragraph> (pen or pencil) <paragraph> (paper or cardboard or plastic or metal or cloth))<in>metadata)

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2006 IEEE -

Indexed by
 Inspec®